



SPECIFICATION

PN: SJK-6I08000F16UCH

深圳市晶科鑫实业有限公司

SHENZHEN CRYSTAL TECHNOLOGY INDUSTRIAL CO., LTD.

VER	DESIGNED	CHECKED	APPROVED
A1	邵丹斌	李相同	刘忠亮

CUSTOMER APPROVAL

SPECIFICATION :	晶振 / 5032 Glass / 8.000MHz		
SJK PN. :	SJK-6I08000F16UCH		
CUSTOMER PN. :			
CHECKED 1	CHECKED 2	APPROVED	DATE
Result: ☐ PASS ☐ FAIL ☐ OTHER			

FEATURE

- 2 pads SMD glass sealed crystal units.
- High reliable environmental performance.
- Tight tolerance and stability parts are available.
- Designed for automatic mounting and reflow soldering.
- Reasonable cost and good delivery performance.
- The best choice of portable PC, PDA, DSC, and USB interface card.
- Contains Pb in sealing glass exempted by RoHS directive.

ELECTRICAL SPECIFICATIONS

Nominal Frequency	8.000MHz
Mode	AT/Fundamental
Frequency Tolerance (at 25°C)	±10ppm
Frequency Stability Over Operating Temperature Characteristics	±100ppm
Operating Temperature Range	-40°C to +125°C
Storage Temperature Range	-55°C to +125°C
Shunt Capacitance (C0)	3.0 PF Max
Driver Level (DL)	100μW Typical
Load Capacitance(CL)	16PF
Equivalent Series Resistance(ESR)	80Ω Max
Aging @25°C first year (Max)	±5ppm/year

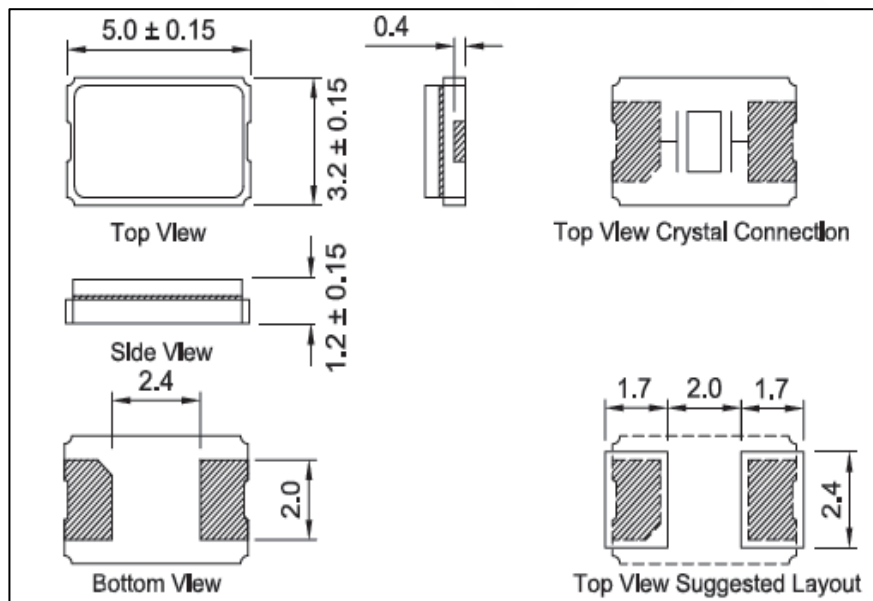
REMARK: SPECIFICATIONS SUBJECT TO CHANGE WITHOUT PRIOR NOTICE,
PLEASE CONFIRM WITH OUR SALES ENGINEER.

Quartz Crystal

SMD Glass 5.0×3.2×1.2mm 6I Series



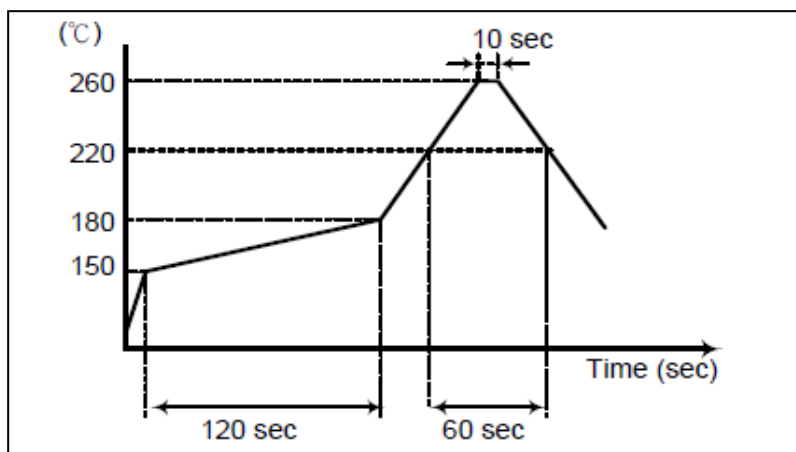
DIMENSION (Unit: mm)



MARK

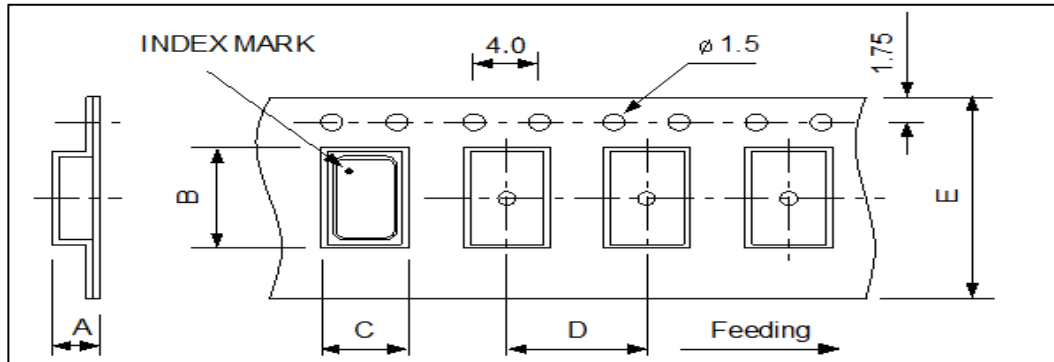


REFLOW CONDITION

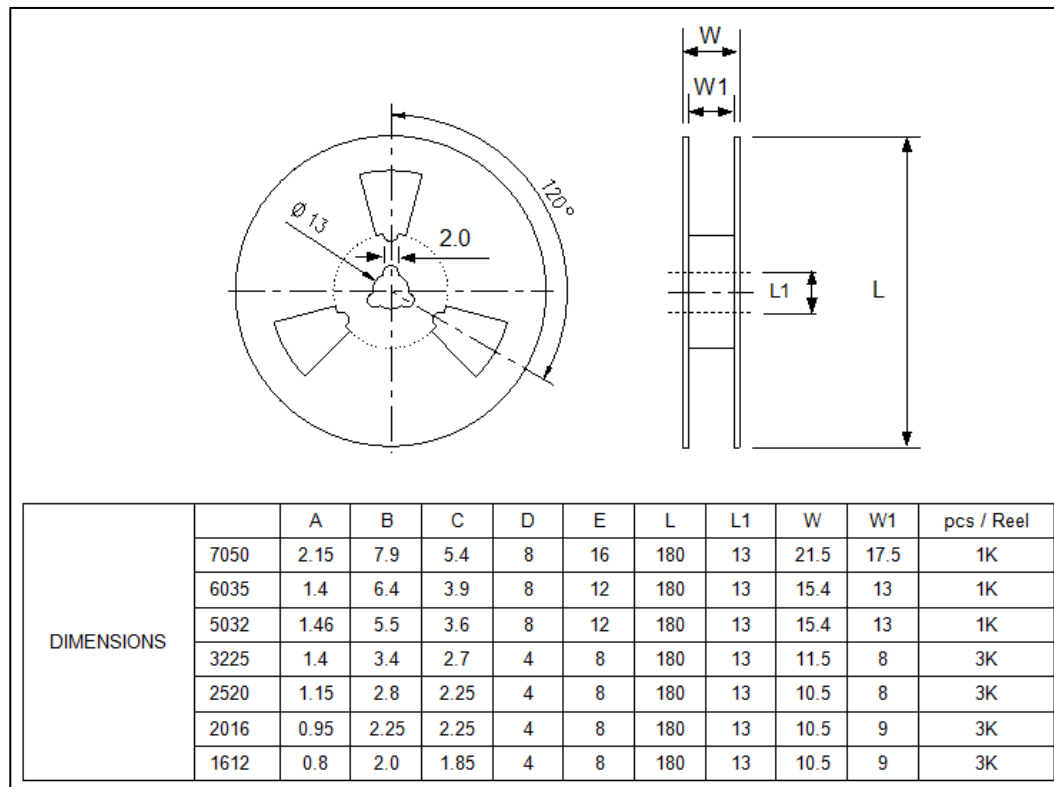


The reflow temperature profile may vary depending on the product model, specifications and frequency range. Refer to the individual product specifications for details.

CARRIER TYPE



REEL



RELIABILITY TEST SPECIFICATIONS

Test item	Equipment	Condition	Specification
1.SOLDERABILITY TEST	SJK-REL001、RC-328A	TP:260℃ TsMax: 200℃ TsMin: 150℃ 2 time 	MIL-STD-883E Method 2003.7
2. HERMETICITY TEST	HELIOT-306S	Pressurized 0.4~0.5Mpa ethanol sealed tank for 10 minutes	MIL-STD-883E Method 1014.10
3. VIBRATION TEST	HG-V4、S&A 250B	Enable Crystal(10g) from 10-55-10Hz,X、Y、Z horizontal,1 Minute vibration/time, 1time/ 2 hours.	MIL-STD-883E Method 2007.3
4. MECHANICAL SHOCK	HPC-200、S&A 250B	Enable Crystal 50G(490m/s ²) time=11 ms speed=3.4 m/s half sine wave oscillation	JIS C6701
5. DROP TEST	HARD BOARD.S&A250B	75cm High,3 times on hard board	MIL-STD-202F Method 213B
6. HIGH&LOW TEMP STORAGE TEST(Static test)	H-PTH-80CK & HM101-3ABN, S&A 350B/250B	High temperature: 125℃±2℃,1000hr; Low temperature:-40℃±3℃,1000hrs	MIL-STD883C, METHOD 1011.8
7. TEMP & HUM CYCLING TEST	H-PTH-80CK CHAMBE, S&A 350B/250B	Temperature:-10℃±2℃~65℃±2℃,Humidity:93±3%,1 cycle need 24 hrs. 5cycles.	MIL-STD-883E Method 1005.8
8. HIGH TEM. & HUM.STORAGE TEST	H-PTH-80CK CHAMBE, S&A350B/250B	Temperature:85℃±2, Humidity:85+3,-2%,Store 96 hrs	JIS C6701
9. AGING TEST	H-PTH-80CK CHAMBE, S&A350B/250	Temperature:85℃±2, Store 1000 hrs	JIS C5023

REVISION RECORD (SJK-6I08000MAF16H0J3)

Rev	Revise contents	Reason	Reviser	Checked	Approved
A1	Initial released	--	贺丹斌	李相同	刘惠光